TOSHIBA Transistor Silicon NPN Epitaxial Type (PCT Process)

# HN1C05FE

Low Frequency Amplifier Applications **Muting Application Switching Application** 

Low Saturation Voltage: VCE(sat)(1)=15mV (Typ.)

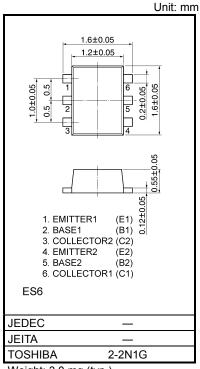
:@  $I_C = 10mA/I_B = 0.5mA$ 

• High Collector Current :IC=400mA(Max.)

### Maximum Ratings (Ta = 25°C) (Q1, Q2 Common)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	$V_{CBO}$	15	V
Collector-emitter voltage	V <sub>CEO</sub>	12	V
Emitter-base voltage	V <sub>EBO</sub>	5	V
Collector current	I <sub>C</sub>	400	mA
Base current	I <sub>B</sub>	50	mA
Collector power dissipation	P <sub>C</sub> *	100	mW
Junction temperature	Tj	150	°C
Storage temperature range	T <sub>stg</sub>	<i>–</i> 55∼150	°C

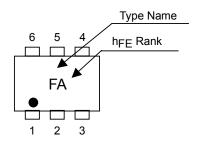
<sup>\*:</sup>Total rating.

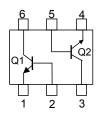


Weight: 3.0 mg (typ.)

# Marking

## **Equivalent Circuit (Top View)**





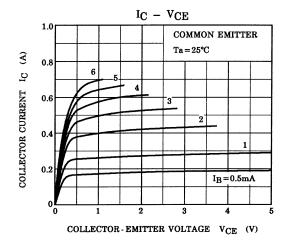
# Electrical Characteristics (Ta = 25°C) (Q1, Q2 Common)

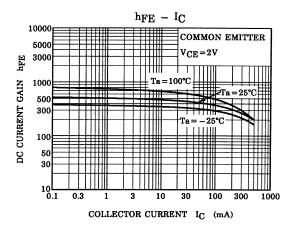
Chara	cteristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Collector cut-off	current	I <sub>CBO</sub>	V <sub>CB</sub> =15V, I <sub>E</sub> = 0	_	_	100	nA	
Emitter cut-off c	urrent	I <sub>EBO</sub>	V <sub>EB</sub> = 5V, I <sub>C</sub> = 0	_	_	100	nA	
DC current gain		h <sub>FE (Note)</sub>	V <sub>CE</sub> = 2V, I <sub>C</sub> = 10mA	300	_	1000		
Collector-emitter saturation voltage		V <sub>CE</sub> (sat)(1)	I <sub>C</sub> = 10mA, I <sub>B</sub> = 0.5mA	_	15	30	- mV	
		V <sub>CE</sub> (sat)(2)	I <sub>C</sub> = 200mA, I <sub>B</sub> = 10mA	_	110	250		
Collector-emitte saturation voltage		V <sub>BE(sat)</sub>	V <sub>CE</sub> = 200mA, I <sub>C</sub> = 10mA	_	0.87	1.2	V	
Transition frequ	ency	f <sub>T</sub>	V <sub>CE</sub> = 2V, I <sub>C</sub> = 10mA	_	130	_	MHz	
Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = 10V, I <sub>E</sub> = 0, f = 1MHz	_	4.2	_	pF	
"ON" resistance		R <sub>on</sub>	I <sub>B</sub> = 1mA,V <sub>in</sub> =1V <sub>rms</sub> ,f=1kHz	_	0.9	_	Ω	
Switching time Storage	Turn on time	<sup>t</sup> on	$0 \xrightarrow{\text{INPUT}} 300\Omega \xrightarrow{\text{OUTPUT}} 10\mu\text{s} \xrightarrow{\text{OS}} 0 \xrightarrow{\text{SO}} 0 \xrightarrow{\text{SO}} 0$ $V_{BB}  V_{CC}$ $= -3V = 6V$ Duty cycle $\leq 2\%$ $ _{B1} = - _{B2} = 5 \text{ mA}$	_	85	_		
	Storage time	<sup>t</sup> stg		_	170	_	ns	
	Fall down time	<sup>t</sup> f		_	40	_		

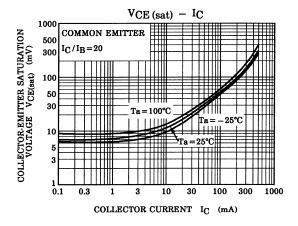
(Note) hFE Classifications A: 300~600, B: 500~1000

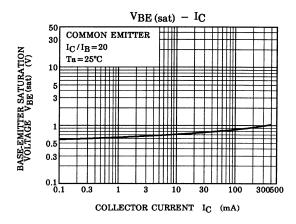
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### (Q1, Q2 Common)



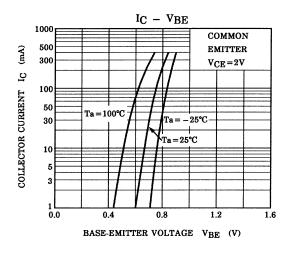


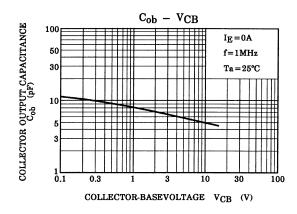


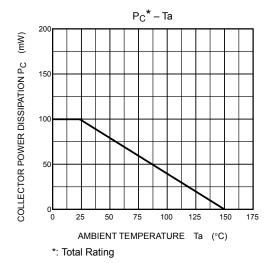


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### (Q1, Q2 Common)







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Handbook" etc..

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